

New Instrument for quantitative measurement and qualitative analysis of metallized films (e. g. for capacitor applications).

- required for production and quality control rooms.

TOMI d. o. o. Črnomelj / Slovenia and ENGICCS GmbH, Hanau / Germany are focused on quantitative measurements and qualitative analysis in the field of metallized film for capacitors & security applications for customers to support and improve current measurement and analysis systems during production.

TOMI.SCAN.03 is a measurement tool with analyzer instrumentation, to characterize the material composition ratio (e.g. aluminum & zinc), optical or image inspection, resistivity and μ -distance coupled with Data Analysis Management (NITOP software).

TOMI.SCAN.03 device measures these properties at the highest accuracy coupled with an impressive analysis of data being processed and reported in real time. The high adaptive measurement probes have been integrated on a linear precision position drive to measure the metallized films.

With the compact design form, TOMI.SCAN provides an unparalleled level of fast data acquisition, measurement reliability and end-user satisfaction (ergonomics) with less human interference. The complete measuring sequence – from the setting of the sample to the print-out or storage of the measurement reports – has been designed to deliver simplicity and process reliability: measuring conditions, parameters and other settings can be saved for the sample type being measured and retrieved at any time.

The measured data is made available in form of batch reports or data file, the latter is transferred to a host computer for analysis. This is converted and represented as charts, graphs to visualize and analyze large chunks of data from the instrument.


The enhanced analytics of the measured data will drive useful adoption of the Internet of Things (IoT). This means reliably offering improved quality and increased productivity of metallized films for diverse applications for capacitor, security and hologram.

“We are enthusiastic about the general sensor quality, the data acquisition & accuracy, evaluation, and we have achieved 30% reduction in measuring time.” – reference customer.

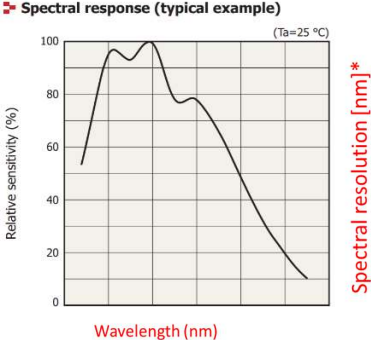
Scope of measurement

Distance /pitch resolution	0.005 mm (25 mm x 19 mm)
Film width measurement	< 1100 mm (up to 0.005 mm) accuracy
Wavelength resolution	12 nm
Spectrum ratio resolution	< 1%
Resistance (Ohm/sq)	0 – 100 Ohm/sq (< 2% accuracy)

Quantitative measurement!
Qualitative Analysis!



Spectral response (typical example)



For more information, please send us an e-mail: info@engiccs.com